

<b>Notice of References Cited</b>	Application/Control No. 09/831,763	Applicant(s)/Patent Under Reexamination MEYER ET AL.	
	Examiner Brian L. Mutschler	Art Unit 1753	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,596,148	07-2003	Belongia et al.	205/99
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Choi et al., "Latent Iron in Silicon," Jpn. J. Appl. Phys., Vol. 40 (2001), pp. L915-L917.
*	V	Istratov et al., "Iron and its complexes in silicon," Appl. Phys. A 69 (1999), pp. 13-44.
*	W	Istratov et al., "Iron contamination in silicon technology," Appl. Phys. A 70 (2000), pp. 489-534.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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